	Instr	CHEMISTRY 3080 4.0 umental Methods of Chemical Analysis
Course Dir	ector: I F e e	Dr. Robert McLaren Petrie Science 301 ext. 30675 -mail: rmclaren@yorku.ca
Office Hou	rs: -	by appointment or T R @ 11:30-12:30pm (DO NOT COME 1 HOUR BEFORE LECTURE)
Course Gra	ading	-,@
	Laboratories	30%
	Research Essa	ay 10%
	Tests (3)	24 %
Pop Quiz or Assignm		Assignments 6 %
	Final Exam	30%
Important	Dates:	
Classes:		Jan 04 - Apr 04 (24 classes)
Exams:		Apr 06 - Apr 29
Labs start:		Jan 18-21 (start)
Tests:		Thurs Feb 3, Thurs March 3, Tues March 29
Research Essay:		Article Approval – Tues Feb 22, Due Date – Thurs March 10
Reading Week (no classes):): Feb 14-18
Chemistry Ski Day:		Feb 17 or 18 (Mount St. Louis)
Meet the Profs night :		Jan 27 (evening)

Tex	tbook: "Principles of Instrumental Analysis", 5th edition,1998 by Skoog, Holler & Nieman, Harcourt Brace Publishers
Ref	erence Books (on reserve in Steacie Science Library):
	"Electronics and instrumentation for scientists", Malmstadt, Enke, Crouch.
	"Electrochemical methods : fundamentals and applications", Bard, Faulkner
	"Instrumental methods of analysis", Willard, Merritt, Dean.
	"Gas chromatography : a practical course" Schomburg.
	"Fundamentals of Analytical Chemistry", 7th ed., Skoog, West, Holler
	"Quantitative Chemical Analysis", 2th ed., D.C. Harris
	"Quantitative Analysis", 6th ed., R.A. Day and A.L. Underwood
	"Analytical Chemistry - Principles and Techniques", L.G. Hargis
Lab	oratories: manuals are available from the lab coordinator, C.Hempstead, 360CCB all laboratory conflicts go through Carolyn .
Note exper backg know prepa	the laboratory portion if the course represents a significant fraction of your final grade. To complete the iments and reports satisfactorily, you must read and understand the experiment in the manual and the ground information in the textbook before coming to the lab. The demonstrators may quiz you on your ledge of the experiment at the beginning of the laboratory. Marks may be deducted for those who are not red.

	Торіс	Chapter			
l)	Introduction	1			
	 instrumental analysis 				
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	C calibration methods				
2)	Electronics, signals and noise	2, 3, 4, 5			
	 basic electronics and device 	es			
	 digital electronics 				
	 computers & interfaces 				
	 signals and noise 				
3)	Analytical Separations	26, 27, 28			
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	 gas chromatography 				
	high performance liquid chromatography				
	other methods				
l)	Analytical Spectroscopy	6 (Review)			
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	 UV/VIS absorbance spectro 	ophotometry			
	 luminescence (fluor-, phos 	phor- and chemilumin-escence)			
	atomic emission and atomic absorption				
5)	Electroanalytical Methods	22, 23, 25			
	 potentiometry 				
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	 the mass spectrometer 				
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Introduction Classification of Analytical Chemistry				
 sepa quar dete prec these 	rations performed by precipitation, solvent extraction or distillation. ntitative analysis performed by gravimetric and volumetric (titrimetric) methods ction limits in the ppb - % range. ision can often be excellent e methods are often labour intensive			
Instru	mental Analysis			
 ofter molecting quantitie detee prection of noise 	n these are semi to fully automated techniques that involve the manipulation of ules, photons and electrons to provide simultaneous (often) qualitative and tative analysis. etion limits in the pp 10-15 - % range ision is dependent less on the operator and more on the instrument and sources se.			





Cont'd

Other Methods

- mass spectrometry (m/e ratio + ion mobility)
- radiochemical
- thermal methods
- surface analysis
- nuclear magnetic resonance (NMR)
- X-Ray spectroscopy

Hyphenated Methods

separation method / detection method

- liquid chromatography + mass spectrometry (LC/MS)
 -Electrophoresis + inductively coupled plasma + mass spectrometry (CE/ICP-MS)

sampling/separation/ion generation/detection method

solid phase microextraction/gas chromatography/electrospray ionization-mass spectrometry (SPME/GC/EI-MS)

Instrumental methods of Chemical Analysis (vs classical techniques)

Advantages

- less labour intensive
- easy to automate
- simultaneous multi component analysis
- fast analysis
- lower detection limits

Disadvantages

- higher expense
- harder to trouble shoot problems, more technical expertise
- black box syndrome













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Sensitivity

Very frequently, the analytical signal, y, is linearly related to the concentration of the analyte, C:

 $y_{analytical} = mC + y_{blank}$

where m = slope C = analyte concentration y_{blank} = signal seen for a sample with no analyte (C=0)

Sensitivity = slope of calibration curve = $m = \Delta y / \Delta C = dy / dC$

(MUST have UNITS!!! ie- signal units concentration⁻¹)

Limits

Detection Limits:

IUPAC definition "the limit of detection, expressed as a concentration c_L (or amount q_L), is derived from the smallest measure, y_L , that can be detected with reasonable certainty for a given analytical procedure." ACS definition "the limit of detection is the lowest concentration of an analyte that an analytical process can reliably detect".

In order to distinguish the blank signal and the signal arising from a small quantity of material, we need to rely on statistics.

 $y_{analytical} = mC + y_{blank}$

A detectable signal, y_{DL} , is one that is different (greater) than the blank signal by a statistically significant amount.

 $y_{analytical} - y_{blank} = mC = k\sigma_{blank}$

Detection Limit, contd

 $mC_{DL} = k \sigma_{blank}$

$$C_{DL} = \frac{k\sigma_{blank}}{m}$$

What value of k ??

If we could average significant values of the blank such that it were a well defined value with a low standard uncertainty, AND if the distribution of errors in the analytical signal are normally distributed, then a difference in signal of 2 s_{blank} is statistically significant at the 95% confidence level. BUT not all distributions are normal AND there can be uncertainty in the blank level if we do not have an infinite number of measurements. For this reason, IUPAC recommends that the detection limit be defined with a value of k=3.

$$C_{DL} = \frac{3\sigma_{blank}}{m}$$

This equation defines the concentration detection limit.

- it also defines why we continually strive to lower the instrumental noise, σ . The lower the noise, the lower is our limit of detection.

We also attempt to lower blank levels....Why? because noise increases with signal level usually...if we lower background level, we lower noise.



Identification Limit

the amount of material that can be *reliably* detected with a reasonable degree of confidence.

By reliably detected, we may mean for example, if a sample with this concentration were put into our instrument, we are statistically confident that we would report the sample as containing a statistically significant amount of analyte the majority of the time...

$$C_{IL} = \frac{6\sigma_{blank}}{m}$$



Limit of Quantification

the amount of material that can be reliably *quantified*, C_q . The signal given by this amount of material is y_q and the uncertainty in the signal is σ_q

Typically, we would like to quantify the concentration of material with a relative uncertainty less than 10%.

$$RSD = \frac{\sigma_{ql}}{y_{ql}} = 0.10 \qquad y_{ql} = \frac{\sigma_{ql}}{0.10} = 10\sigma_{ql} \approx 10\sigma_{blank}$$

If we make the approximation that $\sigma_{ql} \sim \sigma_{blank}$, and m is well known, then:

$$C_{QL} = \frac{10\sigma_{blank}}{m}$$

Analytical Ranges

Dynamic Range:

- the range over which the signal is linear, usually defined from the detection limit to the the point where the signal is no longer linear with concentration.

Useful Range:

- the range over which there is useful quantification, usually defined from the limit of quantification (or identification limit) to the the point where the signal is no longer linear with concentration. (Note - that the useful range does NOT include the detection limit, working at the detection limit is NOT reliable.)

For a general instrumental method, we would like linear dynamic and useful ranges of greater than 2 orders of magnitude...the more the better usually.

-for specific applications we can sometimes get away with less than this:

eg. monitoring CH₄ in natural gas supply where we are measuring a major component that varies by a small amount.

85% < CH₄ < 99%



Methods of Calibration	
1) normal calibration curve (analytical curve)	
2) standard additions	
3) internal standard	
Calibration Curve	
- used for simple matrixes	
 - instrumental signal is measured for a series of calibration solutions of varying analyte concentration. 	
- a least squares fit of the data to a function establishes a workable mathematical relationship.	
- usually the relationship is linear, y=mC + b; if not we must use non-linear least	
squares analysis (ie- polynomial fit)	
How to handle blanks	
i) subtract blank signal from all subsequent signals to establish "corrected" or "net" instrumental signal.	
ii) include blank signals in regression in which case a non zero intercept	
establishes the level of the blank.	
REVIEW - you are expected to know linear least squares analysis and how to	
determine unknown concentration (with error!) from the measurement of unknown. see Skoog Appendix 1 for review of this method.	

Standard additions

- used when matrix is complex and will potentially affect the analyte response (iesensitivity changes, examples- measuring elemental constituents in blood). Procedure

- prepare multiple samples of volume V_x and unknown concentration C_x . We spike each sample with a different volume, V_s , of a prepared standard of our analyte of concentration, C_s . Optionally, we further dilute each spiked sample to total volume V_t . Measure the signal for each spiked sample and plot analytical signal, y, vs. spiked sample concentration, C_s' . The original sample concentration is diluted as well as spike. The moles of spiked standard = $C_s V_s$

$$C_s' = C_s \times \frac{V_s}{V_t} \qquad C_x' = C_x \times \frac{V_x}{V_t}$$

The instrumental signal will be given by:

$$y = m(C_x'+C_s')+y_{blank} \qquad y = mC_s' + (mC_x'+y_{blank})$$

Plot y vs C_s' to get slope, m, and intercept, b. Note intercept, $b = (mC_s' + y_{blank})$ If y_{blank} is negligible, then $b = mC_s'$ OR

$$C_x' = \frac{b}{m}$$
 AND $C_x = \frac{b}{m} \times \frac{V_t}{V_x}$

Standard additions - cont'd

Note: we frequently use very small spike volumes V_s and no dilution. This simplifies our analysis in that the dilution factors disappear from the above eqn's. $V_t \sim V_x$ AND $C_x' \sim C_x$ AND $C_x = b/m$

Limitations

- instrument response must be linear over the expected concentration range and we must assume and verify that $mC_x' >> y_{blank}$.

Applications - wherever matrix effects can be significant,

Example

5.0 mL aliquots of an unkown containing phenoarbital were delivered to 50.0 mL volumetrics. The following volumes of a standard solution of phenoarbital (2.00ug/mL) were then introduced to the volumetrics before diluting to volume: 0.00, 0.50, 1.00, 1.50, 2.00 mL.

The corresponding signals on a fluorometer instrument were: 3.26, 4.80, 6.41, 8.02, 9.56 arbitrary units.

Find the concentration of phenoarbital in the original unknown.



Internal Standard method

- used when sensitive physical variables in analytical measurement are difficult to control. (ie- injection volume in GC, sample flow rate in AA)
- an internal standard is a substance added in a constant amount to all samples, or it may be a major constituent of the sample. I

Procedure

- add equal amount of int. std. to all samples and standards.

- measure analyte and int. std analytical signal for all samples and standards

- the analytical signal, corrected for fluctuations of the physical variable, can be calculated as $\,y_{analyte}^{}/\,y_{int.\,std.}^{}$

$$Plot \quad \frac{y_{analyte}}{y_{int.std.}} \text{ vs } C_{analyte}$$

Limitations

- analyte and int. std. must behave similarly.

- analyte and int. std. signals must be proportional to the physical quantity giving rise to instrumental variations.

- method is limited to methods that can resolve the analyte and int. std. signal simultaneously.

Internal Standard-example

Example: Gas Chromatography

In a separation of benzene and cyclohexane in a hydrocarbon mixture, toluene can be added as an internal standard to EVERY sample and standard. The gas chromatographs will give three peaks. In a normal calibration, our analytical signal is the integrated area of the analyte peak. Using the internal standard, the peak areas for benzene, cyclohexane and toluene A_{ben} , A_{chex} and A_{tol} , are measured for each standard and unknown sample run. The ratio, A_{ben}/A_{tol} is then calculated for each standard and sample (similar for cyclohexane). A least squares analysis of A_{ben}/A_{tol} vs C_{ben} will yield a straight line. The measurement of A_{ben}/A_{tol} for the unkown gives us the concentration of benzene in the unknown sample(s).

Vinj	wt% ben	A_ben	A_tol	A_ben/A_	tol
0.93	1	93() 13950	0.066667	
1.27	2	2540	19050	0.133333	
0.842	4	336	3 12630	0.266667	
0.99	8	792) 14850	0.533333	
1.297	10	1297) 19455	0.666667	
1.27	16	2032	0 19050	1.066667	
1.2	32	3840	18000	2.133333	
1.222	5.4	6598.8	3 18330	0.36	
0.178466	<	relative std deviation	n in injection	volume	





Review of Basic Components and Laws (ohms – Ω) — $(A \land A)$

R - resistance $(ohms - \Omega)$

Ohm's Law: If we apply a voltage across a resistor, the current that flows is inversely proportional to the resistance.

I = V/R or V = IR (voltage *drop* across a resistor)

Power Law: the power (joules s⁻¹) dissipated in a resistive element is given by:

 $\mathbf{P} = \mathbf{I}^2 \mathbf{R} = \mathbf{I} \mathbf{V} = \mathbf{V}^2 / \mathbf{R}$

Kirchoff's Current Law: the algebreic sum of all currents encountered at any instant at a junction must be zero.

$$\mathbf{i}_1 \neq \mathbf{i}_2 \neq \mathbf{i}_3 \qquad \mathbf{I} = \mathbf{i}_1 + \mathbf{i}_2 + \mathbf{i}_3$$

V source (ie- battery)

Kirchoff's Voltage Law: the algebreic sum of the voltages in a closed loop must be zero.

$$V_{source} = \Delta V_{cell} + \Delta V_R + \Delta V_C$$

Series, Parallel Circuits and Voltage Dividers

Series Circuits: all electrical components in the same current path. For resistors in series...

Parallel Circuits: components in parallel current paths with a common voltage. For resistors in parallel.



Voltage Dividers: a combination of elements in series will act as a voltage divider where only a fraction of the total voltage appears across an individual element.



Current Dividers

- a combination of resistors in parallel will act as a current divider. Highest current is through the path of least resistance. $i_T \rightarrow$

$$V_{S} = \Delta V_{1} = \Delta V_{2} = \Delta V_{3} \qquad I_{t} = i_{1} + i_{2} + i_{3} \qquad V_{s} = R_{1} \neq R_{2} \neq R_{3} \neq I_{t}$$

$$I_{t} R_{t} = i_{1}R_{1} = i_{2}R_{2} = i_{3}R_{3}$$

$$i_{1} = \frac{V_{s}}{R_{1}} = \frac{1}{R_{1}} = \frac{1}{R_{1}} = \frac{1}{R_{1}} = \frac{1}{R_{1}} + \frac{1}{R_{2}} + \frac{1}{R_{3}}$$

$$i_{1} = \frac{1}{N_{1}} \times I_{T}$$
Example: V = 15V, R₁ = 100 Ω, R₂ = 200 Ω, R₃ = 300 Ω. What is I_{t}, i_{1}, i_{2}, i_{3}, R_{t}?
Answers. I_t = 0.275A; i_{1} = 0.150A, i_{2} = 0.075A, i_{3} = 0.050A, R_{t} = 54.5 Ω.
The highest current is through the resistor with the lowest resistance.

Voltage Measurements and Loading Errors

The goal in any signal measurement is to minimize the effect of the measurement process on the measured quantity itself. The small error that can result in a voltage measurement is known as a loading error. Any voltage we are measuring could be represented by a voltage source, characterized by the voltage, V_s, and the source impedance, R_s.



The internal impedance (resistance) of the voltage measurement device (ie- a digital volt meter (DVM) meter, R_M , must be much greater than the impedance of the voltage source we are measuring, R_S . This is necessary to ensure that $V_M >> \Delta V_{RS}$. The error in the voltage measurement is given:

 V_{error} = measured voltage – actual source voltage = $V_M - V_S = (V_s - \Delta V_{RS}) - V_s = -\Delta V_{RS}$ The relative error (loading error) in the voltage measurement is given by:

$$err(\%) = \frac{-\Delta V_{RS}}{V_S} \times 100 = \frac{\frac{-R_s}{(R_s + R_M)} \times V_s}{V_s} \times 100 = \frac{-R_s}{(R_s + R_M)} \times 100$$

Current measurements

Current is measured by inserting a standard resistor, R_{STD} , (part of a DMM) into the current path of the circuit being measured. The standard resistor, R_{STD} , must be much smaller than the load resistance, R_L , (and the internal impedance of the voltage measurement circuit of the DMM, R_M) so as not to perturb the magnitude of the current in the circuit before we made the break. Note that the meter becomes part of the circuit, and the current, I_2 flows through the load resistor, R_{STD} .



Resistance measurements

the meter produces a known constant current, I_{STD} , and the voltage drop across the unknown resistor, R_x , is then determined. $R_x = V_x/I_{STD}$. The meter must be capable of producing a constant current that is independent of the unknown resistance. This is usually done in scales.

Digital Multimeters and Oscilloscopes

The heart of the DMM includes a dc digital voltmeter circuit, with the addition of other front end component circuits for $R_{to}V$, $V_{to}V$, $I_{to}V$ conversion and an AC to DC convertor for the measurement of AC signals.

GRAPHIC MISSING

Valuable laboratory apparatus for measuring ac and dc waveforms. One can measure the voltage, waveform shape, phase lag between signals and create x-vs-y plots. An analog oscilloscope is shown below.

GRAPHIV MISSING

Capacitors

Capacitors: a passive electrical component consisting of two metal foils separated by an electrically insulating dielectric medium. The capacitor is capable of storing charge but will not allow current to pass. The amount of charge stored is proportional to the applied voltage difference:

where **Q** = charge (coulombs)

-++

Although capacitors will not allow dc current to *pass*, they will allow AC current to flow in a circuit because of the current required to alternately charge and discharge the capacitor as the voltage changes. ie- differentiating wrt time, we get:

$$I = \frac{dQ}{dt} = \frac{d(CV)}{dt} = C\frac{dV}{dt}$$

 $\mathbf{O} = \mathbf{CV}$

Note that the larger dV/dt, the faster the voltage changes with time, the larger the current that flows to the capacitor. As $dV/dt \rightarrow 0$, $I \rightarrow 0$. ie- if we apply a constant voltage (DC) across a capacitor, no current will flow (at steady state).

Capacitive Reactance:

Capacitors, like resistors, impede the flow of current. Their reactance (also called "impedance", in ohms) is given by:

$$X_C = \frac{1}{2\pi fC} = \frac{1}{\omega C}$$

Note that as $f \rightarrow 0$, $X_C \rightarrow 4 \Omega$. As $f \rightarrow 4$, $X_C \rightarrow 0 \Omega$

















Semiconductors, Doping and Diodes

Doping

Semi-conductors conduct through thermal excitation of electrons across an energy band gap, ΔE . Conductivity increases with temperature (R decresses, see previous page) and can be enhanced in a semiconductor by doping group IV material (ie – Si) with Group V elements (As or Sb) OR Group III elements (Ga or In).

- a semiconductor doped with a group V is n-type since in the crystal lattice, there will be an extra conducting electron. It carries electricity through the movement of negative charge.

- a semiconductor doped with a group III is p-type. It carries electricity through the movement of positive holes

Diodes

- a semiconductor device that behaves as a conductor when current travels in one direction and as a large resistance when current travels the other direction. It is simple a pn junction

PN Junctions: When voltage is biased in one direction, charge can flow freely, electrons in one direction and positive holes in the other. When biased in the other direction, a rapid movement of holes and electrons in the reverse direction gives rise to a depletion region where there are no charge carriers. The resistance of this depletion region is very high. (see graphics in text)

DC Power Supply

Power Supply - graphic

Power Supplies

The purpose of a DC power supply is to provide a source of power (ie-+5V, +10V, +15V) to the instrument to run various electronics and components. An ideal power supply delivers precisely regulated voltage with low output impedance, low ripple, low noise and long lifetime. Many problems in instrumentation can often trace back to the power supply.

Components of a power supply *Switch & overload protection*

- the switch isolates the instrument from the source of power.

- overload protection is provided in the way of a fuse: slow blow, fast blow or circuit breaker. A constantly blowing fuse is a symptom of an electronic problem somewhere in the instrument.

fuses - graphics

Transformer

Purpose is to *step up* or *step down* the AC line voltage. This is accomplished by the way of interwound coils. A time varying current in the primary coil produces a time varying magnetic flux in the second coil, which induces an AC voltage. The transformer equation is given by:

$$V_{\text{sec}} = V_{prim} \times \frac{N_{\text{sec}}}{N_{prim}}$$

where V_{sec} = voltage in secondary coil

 $V_{prim} = voltage in primary coil$

 N_{sec}^{prim} = number of turns in secondary coil

N_{prim} = number of turns in the primary coil

Normally, the transformer is used to divide the voltage. Transformers can also be used to isolate ac signals so to avoid common ground (the sec and prim wires are not connected).

graphic-transformer

Rectifiers

rectifiers produce a ~ dc voltage from an AC input voltage. *Half-Wave Rectifier*

- only half (+) of the ac wave passes through the rectifier because of the bias of the diode. When current does pass through, it's voltage drop is seen across the load resistor.

graphic- 1/2 wave rectifier

Full Wave Rectifier

- more efficient than a HWR since there will be half of the ripple when we smooth the output. There are various types. One example is shown below. Current always flows through the load resistor in one direction, on both the positive and negative cycles. The diodes dictate the current path.

graphic- full wave rectifier circuit

Filters

- an effective way to smooth the output from the rectifier is with a low pass filter. A capacitor in parallel with the load resisitor can accomplish this.

- the larger the capacitor, the higher the average voltage and the smaller will be the ripple. Ripple may be defined by the ripple factor: $r = \frac{V_{AC}}{V_{AC}}$

 $=\frac{1}{V_{DC}}$

where V_{AC} and V_{DC} are the AC and DC components of the output voltage respectively.

graphic- RC filter

graphic- effect of capacitance on ripple

Voltage Regulation

- changes in ac line voltage ($\pm 20\%$) or load current can cause the voltage output of a filtered rectifier to vary significantly. If we require 0.1 or 1% precision in the measured signal in our instrument, this would be unacceptable.

how do we regulate voltage in a power supply?

Zener Diode -this is a diode which is designed to be operated in breakdown mode.

graphic- Zener Diode

Integrated Circuit Voltage Regulator

- the principle is simple as shown below. Components actually contain many internal transistors and devices. The voltage regulators are power rates and require heat sinking.

graphic- IC Voltage regulator









Voltage Follower - cont'd

Another way to derive the voltage follower equation from first principle is as such:

$$v_{o} = -A (v_{o} - v_{+}),$$

$$v_{o} = -A (v_{o} - v_{in}) \quad [\text{since } v_{-} = v_{o}, v_{+} = v_{in}]$$

$$v_{o} (1+A) = A v_{in}$$

$$v_{o} = v_{in} \times \frac{A}{A+1}$$

$$v_{o} \approx v_{in} \times \frac{A}{A}$$

$$v_{o} \approx v_{in}$$



The voltage follower (with gain) has high input impedance, and low output impedance making it valuable an ideal amplifier for high impedance sources (ie-pH meters a), prior to the readout device.





Differential Amplifier – cont'd

Advantage of differential amplifier:

It gets rid of *"common mode noise"*, noise in the form of voltages that are common to both inputs, ie- thermal drift, induced voltages at 60 Hz or other frequencies. These common voltages are subtracted.

Common Mode Rejection ratio (CMRR)

Differential Amplifiers are characterized by how well they can reject common signals. This is called the common mode rejection ratio (the higher the better): where A_{diff} = amplification of difference signals (ie- R_f/R_{in}) and

A_{comm} = amplification of common signals (ie- imperfections)

$$CMRR = \frac{A_{diff}}{A_{comm}}$$

example: $R_f = 50kS, R_{in} = 500S.$

A common voltage source is fed to both inputs by shorting the leads together, $V_1 = V_2 = 1.0$ V. The output, $v_0 = 1$ mV, then we find CMRR as:

 $A_{diff} = R_f / R_{in} = 100$ $A_{comm} = 1mV/1V = 0.001$

CMRR = 100/.001 = 1x10⁵

Mathematical Functions

Addition and Subtraction

These circuits can be used to add voltages or currents. The derivation is easily seen from Kirchoff's law

Integrators: In general, an integrator will attenuate noise, averaging the input voltage over a specified period of time. The output voltage is the time integral of the input signal. 1 t

$$\mathbf{v}_0 = -\frac{\mathbf{I}}{\mathbf{R}_{\rm in}\mathbf{C}_{\rm f}}\int\limits_0^{\rm I} \mathbf{v}_{\rm in} dt$$

Differentiators: In general, a differentiator will amplify noise. They can be used wherever the time rate of change of a signal is required.

The derivation is easy:

$$\mathbf{v}_0 = -\mathbf{I}_f \mathbf{R}_f$$

but
$$I_f = dq/dt = C_{in} dv_{in}/dt$$

$$\mathbf{v}_{\mathrm{o}} = -\mathbf{R}_{\mathrm{f}}\mathbf{C}_{\mathrm{in}}\frac{\mathrm{d}\mathbf{v}_{\mathrm{in}}}{\mathrm{d}t}$$

Note that if the the signal is not changing, current does not flow through the input capacitor. Only ac signals will generate a response.

Mathematical Functions

see Fig 3-14 a,b,c,d

Op-amp applications

Fig 3-9, 3-10, 3-11





Analog to Digital Convertors

Signals and Noise

Noise limits our ability to distinguish between real (ie- chemical) and background signals. As chemists making sensitive measurements, our *call to arms* is:

- i) to understand the noise in the measurement system
- ii) to reduce the noise in the measurement
- iii) to reduce the background signal

Why are ii) and iii) synonymous?..... because noise generally increases with signal (not always).

Signal to noise ratio: $\frac{S}{N} = \frac{\text{mean signal}}{\text{noise}} = \frac{\bar{Y}}{\sigma_y}$

We often measure the quality of a signal measurement by the S/N ratio...the larger the better. At S/N ratios >3, the signal is detectable. Note that,

$$S/N = \frac{Y}{\sigma_y} = \frac{1}{\frac{\sigma_y}{Y}} = \frac{1}{RSD}$$

Sources of Noise

Sources of Noise

Chemical Noise: usually associated with the portion of our measurement system that is external to our instrument, but not always.

- incomplete reactions

- effect of temperature fluctuations on equilibrium

- changes in pressure, relative humidity, light intensity that can alter the concentration of an analyte (these parameters could change the sampling efficiency for example)

Instrumental Noise: noise associated with the instrumental portion of our method.

- Thermal noise

- Shot noise

- Flicker noise

Thermal Noise

noise associated with thermally induced motion in charge carriers, either of the charge carriers or the lattice through which the charge carriers pass (resistor noise). The thermally induced motion results in charge inhomogeneities, giving rise to voltage fluctuations (recall that a voltage is potential energy associated with the separation of charge):

 $V_{\rm rms} = \sqrt{4kTR\Delta k}$

where

k = Boltzmann's constant (1.38054 x 10⁻²³ JK⁻¹) T = temperature (K) R = resistance (ohms)) f = frequency bandwidth (Hz)

Note : the noise is independent of f (white noise).

How do we reduce thermal noise?

1) reduce the temperature (we get ~ factor of 2 reduction in noise by cooling from ambient to liquid N, temp (77K)).

2) reduce the value of the resistors used in circuits (not always practical).

3) reduce the frequency bandwidth (ie-we can add a low pass, high pass, or bandpass filter to reduce the frequencies accepted in the signal processor to only those that are necessary).

Shot Noise (electrical) - noise associated with the movement of charge across a junction (ie- p-n junction, electrolytic cell, photocell). - because the movement of charge across the boundary is random, the number of charges per second (ie- the current) is subject to statistical fluctuations). - usually much smaller than thermal noise. $I_{\rm rms} = \sqrt{2Ie\Delta I}$ current (amps) where T = charge on electron (1.6021 x 10⁻¹⁹ C) e f =frequency bandwidth (Hz) Note : this noise is also independent of f (white noise). How do we reduce shot noise? reduce the frequency bandwidth 1) we can reduce the relative noise, I_{rms}/I, by increasing the current. 2)

Flicker Noise (1/f Noise) - magnitude is inversely proportional to the frequency of the signal (1/f) or to $1/(f)^{\frac{1}{2}}$ - for signals that don't have a discrete frequency, the signal will have noise at all

frequencies that are in the bandwidth of the detector.

- 1/f noise can frequently dominate for f < 100Hz. When f<<1Hz, we call this *drift*.

- although not well understood, 1/f noise appears to be a function of the electronic components used. Metallic film resistors have less 1/f noise than composite resistors; field effect transistors have less 1/f noise than bipolar junction transistors.

Emperical Equation:

f

 $V_{\rm rms} = \sqrt{\frac{{\rm KI}^2}{{\rm f}}}$

where constant dependent on materials used K = I

= dc current (A)

= frequency (Hz)

* Willard et al., Instrumental Methods of Analysis, 7th ed. (1988) pg 17.

How do we reduce flicker noise?

1) avoid DC measurements, go to higher frequencies

2) use better electrical components

Photon or Molecular Shot Noise

when our experimental signal involves the counting of individual items (ie- photons or molecules) and the emission of the photon or molecule is a random event, then we have statistical noise associated with the number of counts, N.

$$\sigma_N = \sqrt{N}$$
 $RSD = \frac{\sigma}{Y} = \frac{\sigma_N}{N} = \frac{\sqrt{N}}{N} = \frac{1}{\sqrt{N}}$

The relative standard deviation is reduced, or the signal to noise ratio is increased, as the number of counts is increased.

Environmental Noise

-results from transfer of energy from our environment to the instrumental system.

-usually confined to specific frequencies

-energy can be from electromagnetic (EM) radiation, mechanical motions, or any other periodic fluctuation (ie- temperature for f <<1Hz.

-the most ubiquitous environmental noise is produced from 60-Hz transmission lines. Noise is seen at 60 Hz and at the harmonics (120, 180, 240 ...).

Distinguishing Signals from Noise

(identical signal levels, differing noise levels)

Environmental Noise

see Fig 5-3 in textbook

Methods for Signal to Noise Enhancement

Hardware methods

Shielding: used for elimination of electromagnetic radiation.

shielded boxes - circuits are often constructed inside metallic boxes which is connected to ground. The box provides a "guassian" shield. No electric fields will penetrate.

Shielded wire - the most common is coax cable. This is used for shielding signals that must be transmitted over a distance. The cable is composed of several layers as shown below

Problems - one has to worry about capacitance at high frequencies. Both sides of the shield are connected to common, resulting in ground loops that can be problematic under certain conditions.

Filtering - discussed previously. Used to eliminate noise in certain frequency ranges.

Differential Amplifiers - discussed previously. Can be used to reject common mode noise.

Modulation/Demodulation

In these methods, we improve our S/N ratio by:

i)modulation - moving our signal to a relatively quiet frequency where there is little noise,

ii) tuned amplification - selectively amplify the signal at the new frequency

iii)demodulation - recovery of the amplitude of the signal. Output is a noise free DC signal.

Example: Spectrophotometric methods

i) chopper

ii) & 3) lock-in amplifier

Software Techniques for reducing Noise (or S/N Enhancement) Boxcar Averaging

For a single point, our signal is: $y_i \pm F$ and $(S/N)_1 = y_i/F$ For a boxcar containing n points:

$$\bar{\mathbf{y}_{i}} = \frac{\sum_{i} \mathbf{y}_{i} \pm \sqrt{\sum \sigma_{i}^{2}}}{N} = \frac{\sum \mathbf{y}_{i}}{N} \pm \frac{\sqrt{N\sigma_{i}^{2}}}{N} = \bar{\mathbf{y}} \pm \frac{\sigma}{\sqrt{N}} \qquad \left(\frac{S}{N}\right)_{N} = \sqrt{N} \times \frac{\bar{\mathbf{y}}}{\sigma}$$

The noise is reduced by a factor of $1/(N)^{1/2}$ and the S/N is increased by $(N)^{1/2}$



